

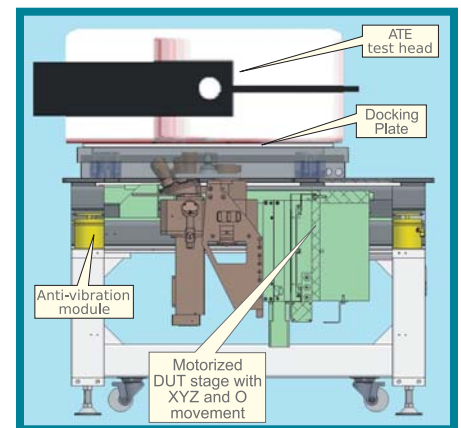
SEMICAPS 5000 CONFIGURATION

DIRECT TESTER-DOCKED WAFER PROBER SYSTEM



Features

- Direct tester-docked for Verigy, Advantest, Teradyne and other ATEs
- Compatible with production probe card up to 5000 pins
- Backside analysis of wafers and wafer parts
- Centric and Aplanatic Refractive Solid Immersion Lens (RSIL) option
- Patent pending wafer support allows RSIL imaging
- Probe landing using optical registration
- CAD interface option
- Fully automatic die-to-die techniques include:
 - Laser Timing Probe (LTP) with frequency mapping for locating signals
 - Scanning Optical Microscopy (SOM) with best-in-class sensitivity for static and dynamic laser induced techniques
 - Photon Emission Microscopy (PEM) with LN2-free, low noise InGaAs or Si-CCD camera



ATE-Docked



Wafer Prober

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